

**Search Notes**

Application/Control No.

10/821,909

Examiner

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Applicant(s)/Patent under  
Reexamination

DOI, YOSHIKI

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	124R	1/23/2006	HN
330	295	1/23/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST UPDATE SEARCH	1/23/2006	HN